

Application/Control No.	Applicant(s)/Patent under Reexamination
09/620,772	KAHN ET AL.
Examiner	Art Unit
Ellen C. Tran	2134

	SEARCHED					
Class	Subclass	Date	Examiner			
380	201	1/18/2007	ET			
380	277	1/18/2007	ΕT			
380	278	1/18/2007	ET			
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	1/18/2007	ET		
NPL - IEEE XPLORE	1/18/2007	ET		
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTION	1/18/2007	ET		
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